

Figure 1: (a) A diffraction Intensity from $(Al_{0.8}Cr_{0.2})_{1-x}$ Si_xN coating shows reflections of the w-AlN and c-CrN phases as well as reflection of the TiN bonding layer. Further analysis of the AlN (100) reflection reveals gradients in FWHM (b) and stress (c).



Figure 2: A SEM image of a representative micro-cantilever prior to testing. L, B and t indicate the cantilever dimensions and the vector P symbolizes the point of loading.